

EiceDRIVER™

2EDN752x / 2EDN852x

Dual Channel 5A, High-Speed, Low-Side Gate Driver With High Negative Input Voltage Capability and Advanced Reverse Current Robustness

EiceDRIVER™

Fast Dual Channel Low-Side Gate Driver

Data Sheet

Revision 2.1, 2016-01-19

Power Management and Multimarket

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Fast Dual Channel 5 A Low-Side Gate Driver

Fast, precise, strong and compatible

- Highly efficient SMPS enabled by 5 ns fast slew rates and 19 ns propagation delay precision for fast MOSFET and GaN switching
- 1 ns channel-to-channel propagation delay accuracy enables safe use of two channels in parallel
- Two independent 5 A channels enable numerous deployment options
- Industry standard packages and pinout ease system-design upgrades

The new Reference in Ruggedness

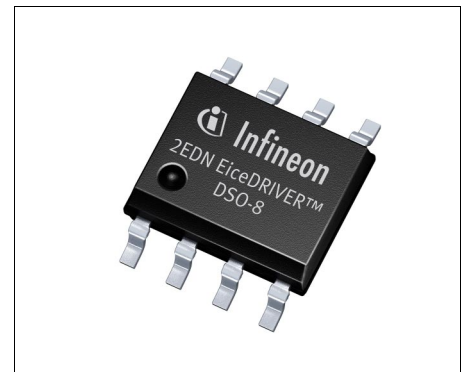
- 4.2 V and 8 V UVLO (Under Voltage Lock Out) options ensure instant MOSFET protection under abnormal conditions
- -10 V control and enable input robustness delivers crucial safety margin when driving pulse-transformers or driving MOSFETs in through hole packaging
- 5 A reverse current robustness eliminates the need for output protection circuitry.

Typical Applications

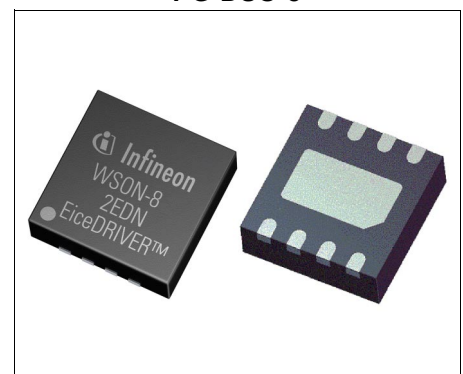
- Server SMPS
- TeleCom SMPS
- DC-to-DC Converter
- Bricks
- Power Tools
- Industrial SMPS
- Motor Control
- Solar SMPS

Example Topologies

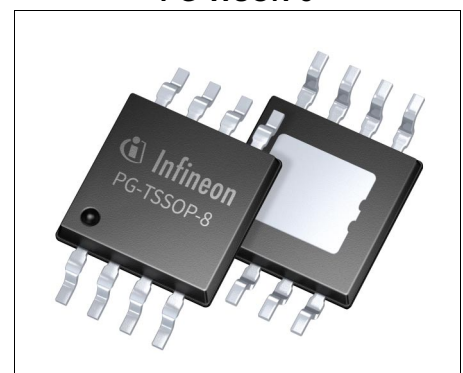
- Single and interleaved PFC
- LLC, ZVS with pulse transformer
- Synchronous Rectification



PG-DSO-8



PG-WSON-8



PG-TSSOP-8

Description

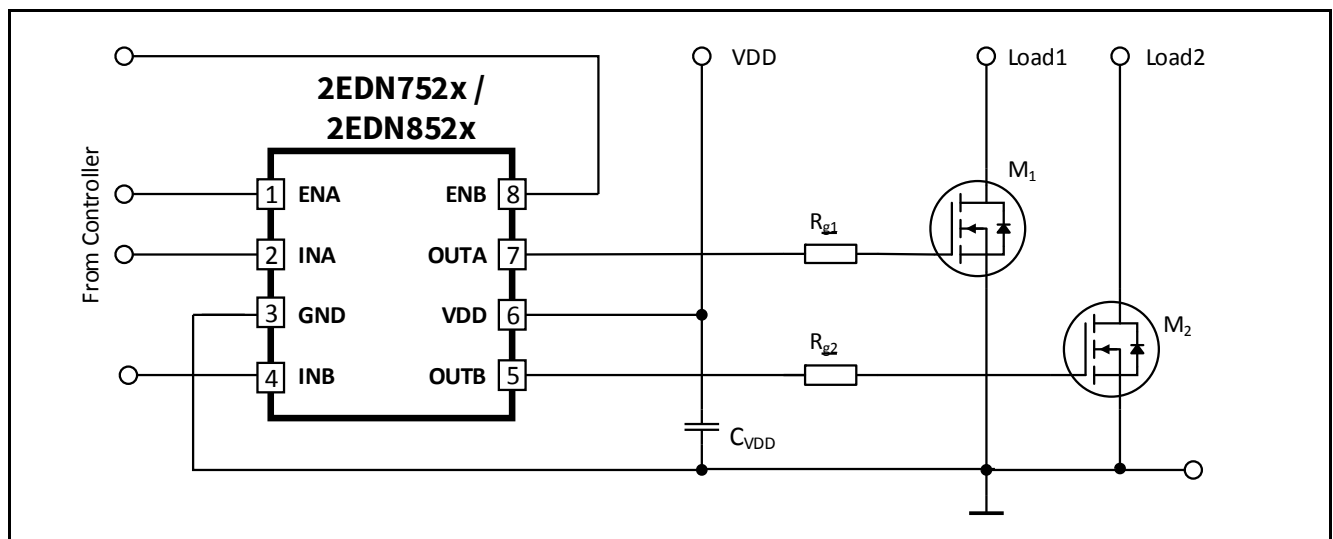
The 2EDN752x/2EDN852x is an advanced dual-channel driver. It is suited to drive logic and normal level MOSFETs and supports OptiMOS™, CoolMOS™, Standard Level MOSFETs, Superjunction MOSFETs, as well as IGBTs and GaN Power devices.

The control and enable inputs are LV-TTL compatible (CMOS 3.3 V) with an input voltage range from -5 V to +20 V. -10 V input pin robustness protects the driver against latch-up or electrical overstress which can be induced by parasitic ground inductances. This greatly enhances system stability.

4.2 V and 8 V UVLO (Under Voltage Lock Out) options ensure instant MOSFET and GaN protection under abnormal conditions. Under such circumstances, this UVLO mechanism provides crucial independence from whether and when other supervisors circuitries detect abnormal conditions.

Each of the two outputs is able to sink and source 5 A currents utilizing a true rail-to-rail stage. This ensures very low on resistance of 0.7 Ω up to the positive and 0.55 Ω down to the negative rail respectively. Very tight channel to channel delay matching, typ. 1 ns, permits parallel use of two channels, leading to a source and sink capability of 10 A. Industry leading reverse current robustness eliminates the need for Schottky diodes at the outputs and reduces the bill-of-material.

The pinout of the 2EDN family is compatible with the industry standard. Two different control input options, non-inverted and inverted, offer high flexibility. Three package variants, DSO 8-pin, TSSOP 8-pin, WSON 8-pin, allow optimization of PCB board space usage and thermal characteristics.


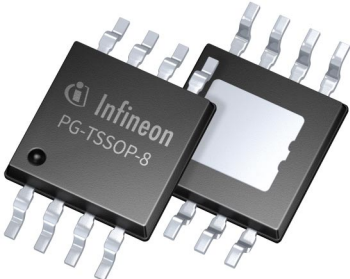
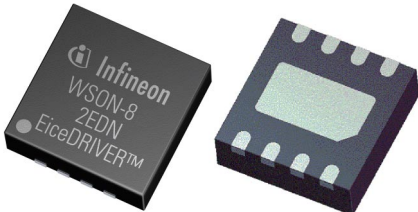


Product Versions

1 Product Versions

The 2EDN752x / 2EDN852x are available in 2 different logic, 2 different undervoltage lockout and 3 package versions.

Table 1-1 Product Versions

| Package | Type. UVLO | Control Input | Part Number | IC Topside Marking Code |
|---|-------------|---------------|-------------|---------------------------------|
| PG-DSO-8 | | | | |
|  | 4.2V | direct | 2EDN7524F | 2N7524AF EiceDRIV XXHYYWW |
| | | inverted | 2EDN7523F | 2N7523AF EiceDRIV XXHYYWW |
| | 8V | direct | 2EDN8524F | 2N8524AF EiceDRIV XXHYYWW |
| | | inverted | 2ED87523F | 2N8523AF EiceDRIV XXHYYWW |
| PG-TSSOP-8 | | | | |
|  | 4.2V | direct | 2EDN7524R | 2N7524 AR_XXX HYYWW |
| | | inverted | 2EDN7523R | 2N7523 AR_XXX HYYWW |
| | 8V | direct | 2EDN8524R | 2N8524 AR_XXX HYYWW |
| | | inverted | 2ED87523R | 2N8523 AR_XXX HYYWW |
| PG-WSO-8 | | | | |
|  | 4.2V | direct | 2EDN7524G | 2N7524 AR_XXX HYYWW |
| | | inverted | 2EDN7523G | 2N7523 AR_XXX HYYWW |
| | | | | |

Product Versions

1.1 Undervoltage Lockout Versions

The two Undervoltage Lockout versions are indicated by the variable x in the product version 2EDNy52x:

- y=7: lower voltage for logic level MOSFETs (4.2 V)
- y=8: higher voltage for standard and superjunction MOSFETs (8.0 V)

Please refer to the functional description section for more details in [Chapter 4 Undervoltage Lockout \(UVLO\)](#).

1.2 Logic Versions

The 2 logic versions are indicated by the variable x in the product version 2EDNy52x:

- x=3: inverting
- x=4: non-inverting

The logic relations between inputs, enable pins and outputs are given in [Table 1-2](#) for the inverting and non-inverting version 2EDNx523 and 2EDNx524. The state of the driving output is defined by the state of the respective input, if the enable inputs ENA and ENB are high (or left open). A logic “low” at an enable input or an undervoltage lockout event, due to low voltage at VDD, causes the respective output to be low too, regardless of the input signal.

Table 1-2 Logic Table

| Inputs | | | | | Output Inverting | | Output non-inverting | |
|--------|-----|-----|-----|--------------------|------------------|------|----------------------|------|
| ENA | ENB | INA | INB | UVLO ¹⁾ | OUTA | OUTB | OUTA | OUTB |
| x | x | x | x | active | L | L | L | L |
| L | L | x | x | inactive | L | L | L | L |
| H | L | L | x | inactive | H | L | L | L |
| H | L | H | x | inactive | L | L | H | L |
| L | H | x | L | inactive | L | H | L | L |
| L | H | x | H | inactive | L | L | L | H |
| H | H | L | L | inactive | H | H | L | L |
| H | H | H | L | inactive | L | H | H | L |
| H | H | L | H | inactive | H | L | L | H |
| H | H | H | H | inactive | L | L | H | H |

1) Inactive means that V_{DD} is above UVLO threshold voltage and release logic to control output stage.
Active means that UVLO disable active the output stages.

1.3 Package Versions

The logic and UVLO versions are available in 3 different packages.

- a standard PG-DSO-8 (designated by “F”)
- a leadless PG-WSON-8 (designated by “G”)
- a small PG-TSSOP-8 (designated by “R”)

Drawings can be viewed in [Chapter 8 Outline Dimensions](#).

Pin Configuration and Description

2 Pin Configuration and Description

The pin configuration for the inverting and standard input version of 2EDN7524F and 2EDN7523F in the PG-DSO-8 package is shown in [Figure 2-1](#).

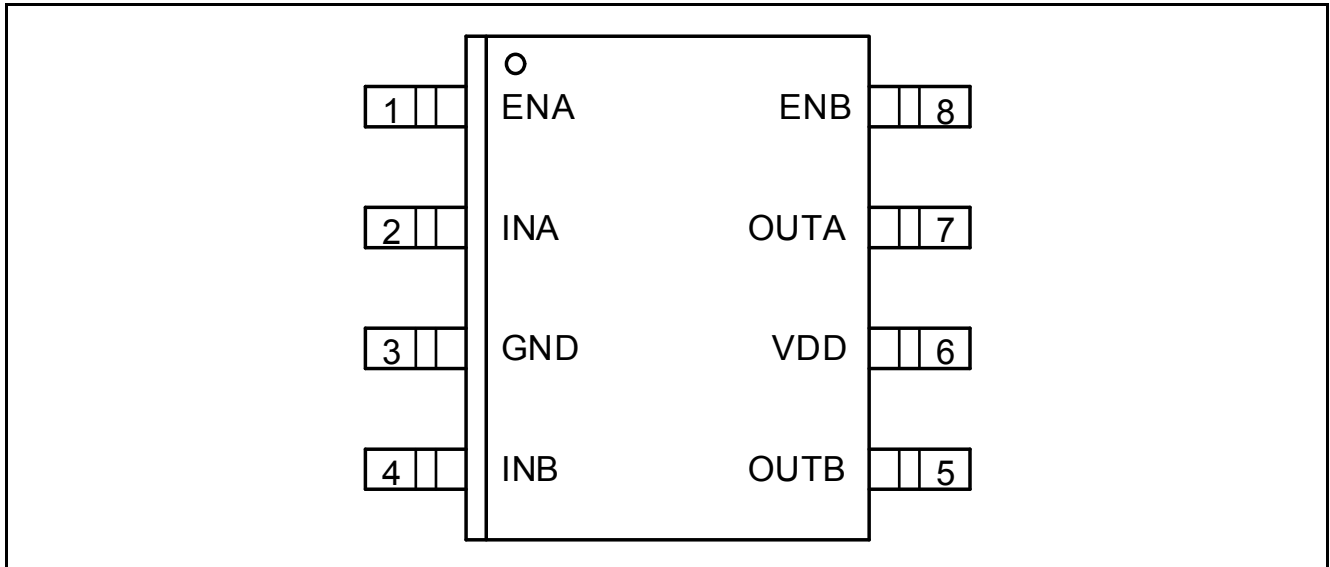


Figure 2-1 Pin Configuration PG-DSO-8, Top View

Table 2-1 Pin Configuration 2EDN7524F and 2EDN7523F in the PG-DSO-8 Package

| Pin | Symbol | Description |
|-----|--------|--|
| 1 | ENA | Enable input channel A Logic input; if ENA is high or left open, OUTA is controlled by INA; ENA low causes OUTA low |
| 2 | INA | Input signal channel A Logic input, controlling OUTA (inverting or non-inverting) |
| 3 | GND | Ground |
| 4 | INB | Input signal channel B Logic input, controlling OUTB (inverting or non-inverting) |
| 5 | OUTB | Driver output channel B Low-impedance output with source and sink capability |
| 6 | VDD | Positive supply voltage Operating range 4.5 V to 20 V |
| 7 | OUTA | Driver output channel A Low-impedance output with source and sink capability |
| 8 | ENB | Enable input channel B Logic Input; if ENB is high or left open, OUTB is controlled by INB; ENB low causes OUTB low |

Pin Configuration and Description

The pin configuration for standard input version of 2EDN7524R, 2EDN8524R, 2EDN7523R and 2EDN8523R in the PG-TSSOP-8 package is shown in [Figure 2-2](#).

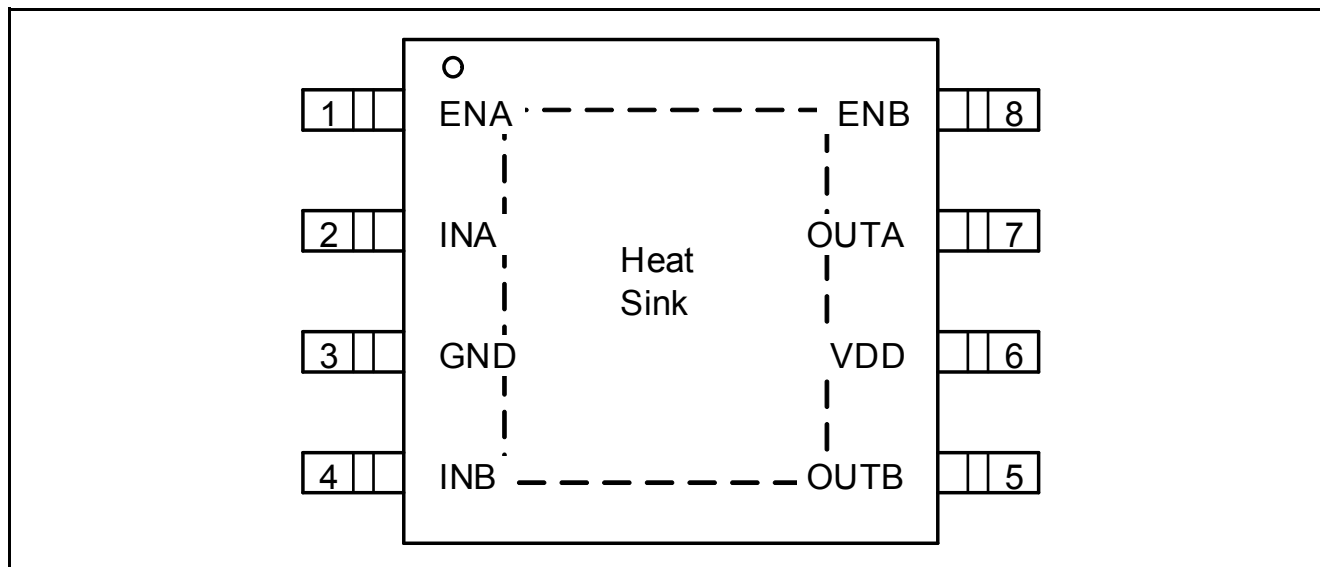


Figure 2-2 Pin Configuration PG-TSSOP-8, Top View

Table 2-2 Pin Configuration 2EDN7524R, 2EDN8524R, 2EDN7523R and 2EDN8523R in the PG-TSSOP-8 Package

| Pin | Symbol | Description |
|-----|--------|--|
| 1 | ENA | Enable input channel A Logic input; if ENA is high or left open, OUTA is controlled by INA; ENA low causes OUTA low |
| 2 | INA | Input signal channel A Logic input, controlling OUTA (non-inverting) |
| 3 | GND | Ground |
| 4 | INB | Input signal channel B Logic input, controlling OUTB (non-inverting) |
| 5 | OUTB | Driver output channel B Low-impedance output with source and sink capability |
| 6 | VDD | Positive supply voltage Operating range 4.5 V to 20 V |
| 7 | OUTA | Driver output channel A Low-impedance output with source and sink capability |
| 8 | ENB | Enable input channel B Logic Input; if ENB is high or left open, OUTB is controlled by INB; ENB low causes OUTB low |

Heat sink of PG-TSSOP-8 packages has to be connected to GND pin.

Pin Configuration and Description

The pin configuration for standard input version of 2EDN7524G and 2EDN7523G. In the PG-WSON-8 package is shown in **Figure 2-3**.

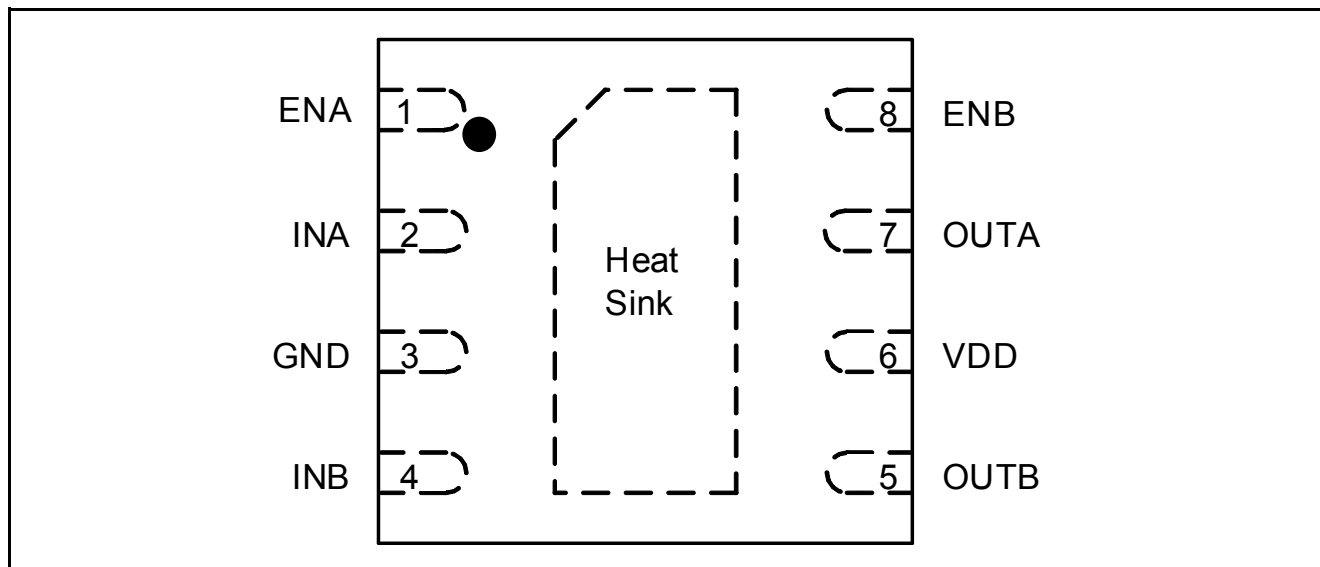


Figure 2-3 Pin Configuration PG-WSON-8, Top View

Table 2-3 Pin Configuration 2EDN7524G and 2EDN7523G in the PG-WSON-8 Package

| Pin | Symbol | Description |
|-----|--------|--|
| 1 | ENA | Enable input channel A Logic input; if ENA is high or left open, OUTA is controlled by INA; ENA low causes OUTA low |
| 2 | INA | Input signal channel A Logic input, controlling OUTA (non-inverting) |
| 3 | GND | Ground |
| 4 | INB | Input signal channel B Logic input, controlling OUTB (non-inverting) |
| 5 | OUTB | Driver output channel B Low-impedance output with source and sink capability |
| 6 | VDD | Positive supply voltage Operating range 4.5 V to 20 V |
| 7 | OUTA | Driver output channel A Low-impedance output with source and sink capability |
| 8 | ENB | Enable input channel B Logic Input; if ENB is high or left open, OUTB is controlled by INB; ENB low causes OUTB low |

Heat sink of PG-WSON-8 packages has to be connected to GND pin.

Block Diagram

3 Block Diagram

A simplified functional block diagram for the **non-inverted version** is given in **Figure 3-1**

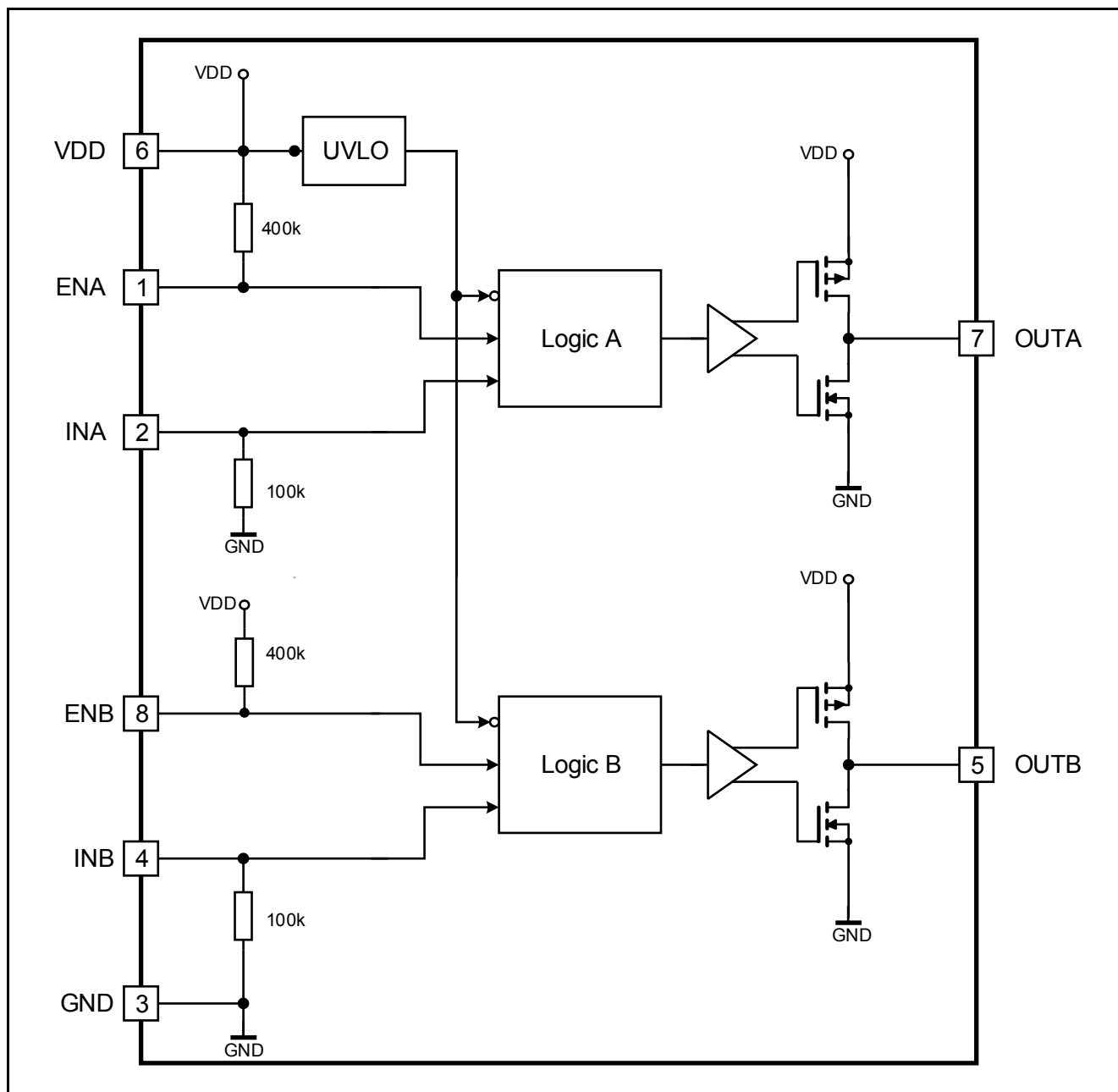


Figure 3-1 Block Diagram, standard input, pull-up/pull-down resistor configuration

Block Diagram

A simplified functional block diagram for the **inverted version** is given in **Figure 3-2**.

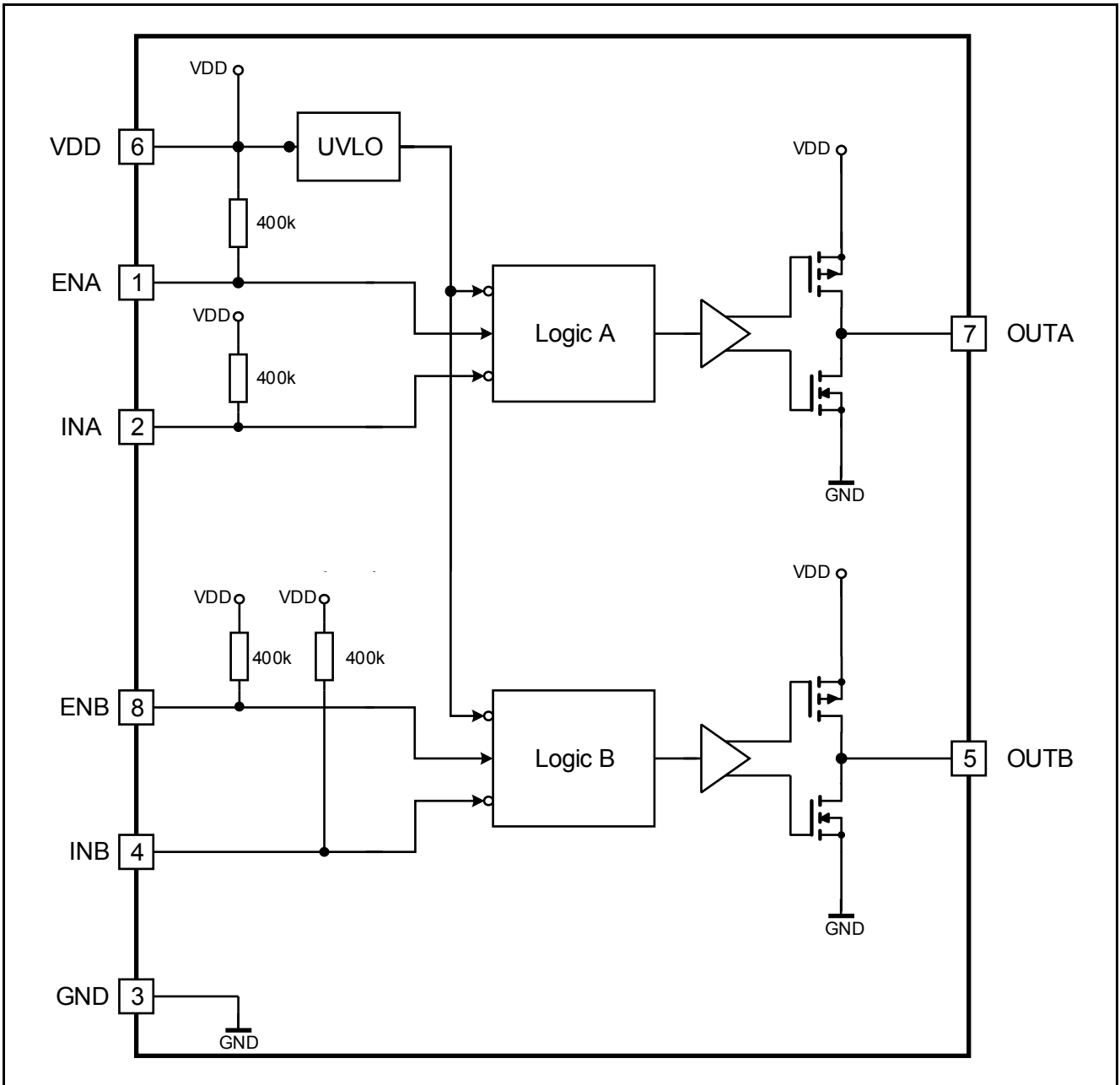


Figure 3-2 Block Diagram, inverting input, pull-up/pull-down resistor configuration

4 Functional Description

4.1 Introduction

The 2EDN752x / 2EDN852x is a fast dual-channel driver for low-side switches. Two true rail-to-rail output stages with very low output impedance and high current capability are chosen to ensure highest flexibility and cover a high variety of applications.

The focus on robustness at the input and output side additionally gives this device a safety margin in critical abnormal situations. An extended negative voltage range protects input pins against ground shifts. No current flows over the ESD structure in the IC during a negative input level. All outputs are robust against reverse current. The interaction with the power MOSFET, even reverse reflected power will be handled by the strong internal output stage.

All inputs are compatible with LV-TTL signal levels. The threshold voltages with a typical hysteresis of 1.1 V are kept constant over the supply voltage range.

Since the 2EDN752x / 2EDN852x aims particularly at fast-switching applications, signal delays and rise/fall times have been minimized. Special effort has been made towards minimizing delay differences between the 2 channels to very low values of typically 1 ns.

4.2 Supply Voltage

The maximum supply voltage is 20 V. This high voltage can be valuable in order to exploit the full current capability of 2EDN752x / 2EDN852x when driving very large MOSFETs. The minimum operating supply voltage is set by the undervoltage lockout function to a typical default value of 4.2 V or of 8 V. This lockout function protects power MOSFETs from running into linear mode with subsequent high power dissipation.

4.3 Input Configurations

As described in [Chapter 1](#), 2EDN752x / 2EDN852x is available in 2 different configurations with respect to the logic configuration of the 4 input pins (input plus enable).

The enable inputs are internally pulled up to a logic high voltage, i.e. the driver is enabled with these pins left open. The direct PWM inputs are internally pulled down to a logic low voltage. This prevents a switch-on event during power up and a not driven input condition. Version with inverted PWM input have an internal pull up resistor to prevent unwanted switch-on.

All inputs are compatible with LV-TTL levels and provide a hysteresis of 1.1V typ. This hysteresis is independent of the supply voltage.

All input pins have a negative extended voltage range. This prevents cross current over single wires during GND shifts between signal source (controller) and driver input.

4.4 Driver Outputs

The two rail-to-rail output stages realized with complementary MOS transistors are able to provide a typical 5 A of sourcing and sinking current. This driver output stage has a shoot through protection and current limiting behavior. After a switching event, current limitation is raised up to achieve the typical current peak for an excellent fast reaction time of the following power MOS transistor.

Functional Description

The output impedance is very low with a typical value below 0.7Ω for the sourcing p-channel MOS and 0.5Ω for the sinking n-channel MOS transistor. The use of a p-channel sourcing transistor is crucial for achieving true rail-to-rail behaviour and avoiding a source follower's voltage drop.

Gate Drive Outputs held active low in case of floating inputs ENx, INx or during startup or power down once UVLO is not exceeded. Under any situation, startup, UVLO or shutdown, outputs are held under defined conditions.

4.5 Undervoltage Lockout (UVLO)

The Undervoltage Lockout function ensures that the output can be switched to its high level only if the supply voltage exceeds the UVLO threshold voltage. Thus it can be guaranteed, that the switch transistor is not switched on if the driving voltage is too low to completely switch it on, thereby avoiding excessive power dissipation.

The UVLO level is set to a typical value of $4.2 \text{ V} / 8 \text{ V}$ (with hysteresis). UVLO of 4.2 V is normally used for logic level based MOSFETs. For higher level, like standard and high voltage superjunction MOSFETs, an UVLO voltage of typical 8 V is available.

Characteristics

5 Characteristics

The absolute maximum ratings are listed in [Table 5-1](#). Stresses beyond these values may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

5.1 Absolute Maximum Ratings

Table 5-1 Absolute Maximum Ratings

| Parameter | Symbol | Values | | | Unit | Note or Test Condition |
|---|----------------------------------|--------|------|---------------|----------|---|
| | | Min. | Typ. | Max. | | |
| Positive supply voltage | V_{VDD} | -0.3 | | 22 | V | |
| Voltage at pins INA, INB, ENA, ENB | V_{IN} | -10 | | 22 | V | |
| Voltage at pins OUTA, OUTB | V_{OUT} | -0.3 | | $V_{VDD}+0.3$ | V | Note ¹⁾ |
| Reverse current peak at pins OUTA, OUTB | I_{SNK_rev} I_{SRC_rev} | | | -5 5 | A_{pk} | < 500ns |
| Junction temperature | T_J | -40 | | 150 | °C | |
| Storage temperature | T_S | -55 | | 150 | °C | |
| ESD capability | V_{ESD} | | | 1.5 | kV | Charged Device Mode (CDM) ²⁾ |
| ESD capability | V_{ESD} | | | 2.5 | kV | Human Body Model (HBM) ³⁾ |

1) Voltage spikes resulting from reverse current peaks are allowed.

2) According to JESD22-C101

3) According to JESD22-A114

5.2 Thermal Characteristics

Table 5-2 Thermal Characteristics

| Parameter | Symbol | Values | | | Unit | Note or Test Condition |
|---|-----------------|--------|------|------|------|---------------------------------|
| | | Min. | Typ. | Max. | | |
| Thermal resistance junction-ambient ¹⁾ | R_{thJA25} | | 125 | | K/W | PG-DSO-8, $T_{amb}=25^{\circ}C$ |
| Thermal resistance junction-case (top) ²⁾ | R_{thJC25} | | 66 | | K/W | PG-DSO-8, $T_{amb}=25^{\circ}C$ |
| Thermal resistance junction-board ³⁾ | R_{thJB25} | | 62 | | K/W | PG-DSO-8, $T_{amb}=25^{\circ}C$ |
| Characterization parameter junction-top ⁴⁾ | Ψ_{thJC25} | | 16 | | K/W | PG-DSO-8, $T_{amb}=25^{\circ}C$ |
| Characterization parameter junction-board ⁵⁾ | Ψ_{thJB25} | | 55 | | K/W | PG-DSO-8, $T_{amb}=25^{\circ}C$ |

Characteristics

Table 5-2 Thermal Characteristics

| Parameter | Symbol | Values | | | Unit | Note or Test Condition |
|---|-----------------|--------|------|------|------|-----------------------------------|
| | | Min. | Typ. | Max. | | |
| Thermal resistance junction-ambient ¹⁾ | R_{thJA25} | | 64 | | K/W | PG-TSSOP-8, $T_{amb}=25^{\circ}C$ |
| Thermal resistance junction-case (top) ²⁾ | R_{thJP25} | | 56 | | K/W | PG-TSSOP-8, $T_{amb}=25^{\circ}C$ |
| Thermal resistance junction-board ³⁾ | R_{thJB25} | | 55 | | K/W | PG-TSSOP-8, $T_{amb}=25^{\circ}C$ |
| Characterization parameter junction-top ⁴⁾ | Ψ_{thJC25} | | 9 | | K/W | PG-TSSOP-8, $T_{amb}=25^{\circ}C$ |
| Characterization parameter junction-board ⁵⁾ | Ψ_{thJB25} | | 13 | | K/W | PG-TSSOP-8, $T_{amb}=25^{\circ}C$ |
| Thermal resistance junction-ambient ¹⁾ | R_{thJA25} | | 61 | | K/W | PG-WSON-8, $T_{amb}=25^{\circ}C$ |
| Thermal resistance junction-case (top) ²⁾ | R_{thJP25} | | 54 | | K/W | PG-WSON-8, $T_{amb}=25^{\circ}C$ |
| Thermal resistance junction-board ³⁾ | R_{thJB25} | | 52 | | K/W | PG-WSON-8, $T_{amb}=25^{\circ}C$ |
| Characterization parameter junction-top ⁴⁾ | Ψ_{thJC25} | | 8 | | K/W | PG-WSON-8, $T_{amb}=25^{\circ}C$ |
| Characterization parameter junction-board ⁵⁾ | Ψ_{thJB25} | | 11 | | K/W | PG-WSON-8, $T_{amb}=25^{\circ}C$ |

- 1) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
- 2) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.
- 3) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.
- 4) The characterization parameter junction-top, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining R_{th} , using a procedure described in JESD51-2a (sections 6 and 7).
- 5) The characterization parameter junction-board, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining R_{th} , using a procedure described in JESD51-2a (sections 6 and 7).

5.3 Operating Range

Table 5-3 Operating Range

| Parameter | Symbol | Values | | | Unit | Note or Test Condition |
|----------------|-----------|--------|------|------|------|------------------------|
| | | Min. | Typ. | Max. | | |
| Supply voltage | V_{VDD} | 4.5 | | 20 | V | Min. defined by UVLO |

Characteristics

Table 5-3 Operating Range

| Parameter | Symbol | Values | | | Unit | Note or Test Condition |
|----------------------|----------|--------|------|------|------|------------------------|
| | | Min. | Typ. | Max. | | |
| Logic input voltage | V_{IN} | -5 | | 20 | V | |
| Junction temperature | T_J | -40 | | 150 | °C | 1) |

1) Continuous operation above 125 °C may reduce life time.

5.4 Electrical Characteristics

Unless otherwise noted, min./max. values of characteristics are the lower and upper limits respectively. They are valid within the full operating range. The supply voltage is $V_{VDD} = 12$ V. Typical values are given at $T_J = 25$ °C.

Table 5-4 Power Supply

| Parameter | Symbol | Values | | | Unit | Note or Test Condition |
|-----------------------|--------------|--------|------|------|------|------------------------------|
| | | Min. | Typ. | Max. | | |
| VDD quiescent current | I_{VDDqu1} | 0.5 | 0.7 | 1.2 | mA | OUT = high, $V_{VDD} = 12$ V |
| VDD quiescent current | I_{VDDqu2} | 0.3 | 0.48 | 0.7 | mA | OUT = low, $V_{VDD} = 12$ V |

Table 5-5 Undervoltage Lockout for Logic Level MOSFET

| Parameter | Symbol | Values | | | Unit | Note or Test Condition |
|--|--------------|--------|------|------|------|------------------------|
| | | Min. | Typ. | Max. | | |
| Undervoltage Lockout (UVLO) turn on threshold | $UVLO_{on}$ | 3.9 | 4.2 | 4.5 | V | |
| Undervoltage Lockout (UVLO) turn off threshold | $UVLO_{off}$ | 3.6 | 3.9 | 4.2 | V | |
| UVLO threshold hysteresis | $UVLO_{hys}$ | | 0.3 | | V | |

Table 5-6 Undervoltage Lockout for Standard and Superjunction MOSFET Version

| Parameter | Symbol | Values | | | Unit | Note or Test Condition |
|--|--------------|--------|------|------|------|------------------------|
| | | Min. | Typ. | Max. | | |
| Undervoltage Lockout (UVLO) turn on threshold | $UVLO_{on}$ | 7.4 | 8.0 | 8.6 | V | |
| Undervoltage Lockout (UVLO) turn off threshold | $UVLO_{off}$ | 6.5 | 7.0 | 7.5 | V | |
| UVLO threshold hysteresis | $UVLO_{hys}$ | — | 1.0 | — | V | |

Characteristics

Table 5-7 Logic Inputs INA, INB, ENA, ENB

| Parameter | Symbol | Values | | | Unit | Note or Test Condition |
|---|-----------|--------|------|------|------------|------------------------|
| | | Min. | Typ. | Max. | | |
| Input voltage threshold for transition LH | V_{INH} | 1.9 | 2.1 | 2.3 | V | |
| Input voltage threshold for transition HL | V_{INL} | 0.8 | 1.0 | 1.2 | V | |
| Input pull up resistor ¹⁾ | R_{INH} | | 400 | | k Ω | |
| Input pull down resistor ²⁾ | R_{INL} | | 100 | | k Ω | |

1) Inputs with initial high logic level

2) Inputs with initial low logic level

Table 5-8 Static Output Characteristics (see Figure 6-2)

| Parameter | Symbol | Values | | | Unit | Note or Test Condition |
|---|-----------------|--------|------|---------------|----------|------------------------|
| | | Min. | Typ. | Max. | | |
| High Level (Sourcing) Output Resistance | R_{on_SRC} | 0.35 | 0.7 | 1.2 | Ω | $I_{SRC} = 50mA$ |
| High Level (Sourcing) Output Current | I_{SRC_Peak} | | 5.0 | ¹⁾ | A | |
| Low Level (Sinking) Output Resistance | R_{on_SNK} | 0.28 | 0.55 | 1.0 | Ω | $I_{SNK} = 50mA$ |
| High Level (Sinking) Output Current | I_{SNK_peak} | | -5.0 | ²⁾ | A | |

1) Active limited by design at approx. $6.5A_{pk}$, parameter is not subject to production test - verified by design / characterization, max. power dissipation must be observed

2) Active limited by design at approx. $-6.5A_{pk}$, parameter is not subject to production test - verified by design / characterization, max. power dissipation must be observed

Characteristics

Table 5-9 Dynamic Characteristics (see Figure 6-1, Figure 6-2, Figure 6-3 and Figure 6-4)

| Parameter | Symbol | Values | | | Unit | Note or Test Condition |
|---|-----------------|--------|------|-----------|------|---|
| | | Min. | Typ. | Max. | | |
| Input/Enable to output propagation delay | T_{PDON} | 15 | 19 | 25 | ns | $C_{LOAD} = 1.8 \text{ nF}, V_{VDD} = 12 \text{ V}$ |
| Input/Enable to output propagation delay | T_{PDOFF} | 15 | 19 | 25 | ns | $C_{LOAD} = 1.8 \text{ nF}, V_{VDD} = 12 \text{ V}$ |
| Input/Enable to output propagation delay mismatch between the two channels on the same IC | Δt_{PD} | | 1 | 4 | ns | |
| Rise Time | T_{RISE} | — | 5.3 | $10^{1)}$ | ns | $C_{LOAD} = 1.8 \text{ nF}, V_{VDD} = 12 \text{ V}$ |
| Fall Time | T_{FALL} | — | 4.5 | $10^{1)}$ | ns | $C_{LOAD} = 1.8 \text{ nF}, V_{VDD} = 12 \text{ V}$ |
| Minimum input pulse width that changes output state | T_{PW} | — | 10 | 20 | ns | $C_{LOAD} = 1.8 \text{ nF}, V_{VDD} = 12 \text{ V}$ |

1) Parameter verified by design, not 100% tested in production.

Timing Diagrams

6 Timing Diagrams

Figure 6-1 shows the definition of rise, fall and delay times for the inputs of the non-inverting version (with Enable pin high or open).

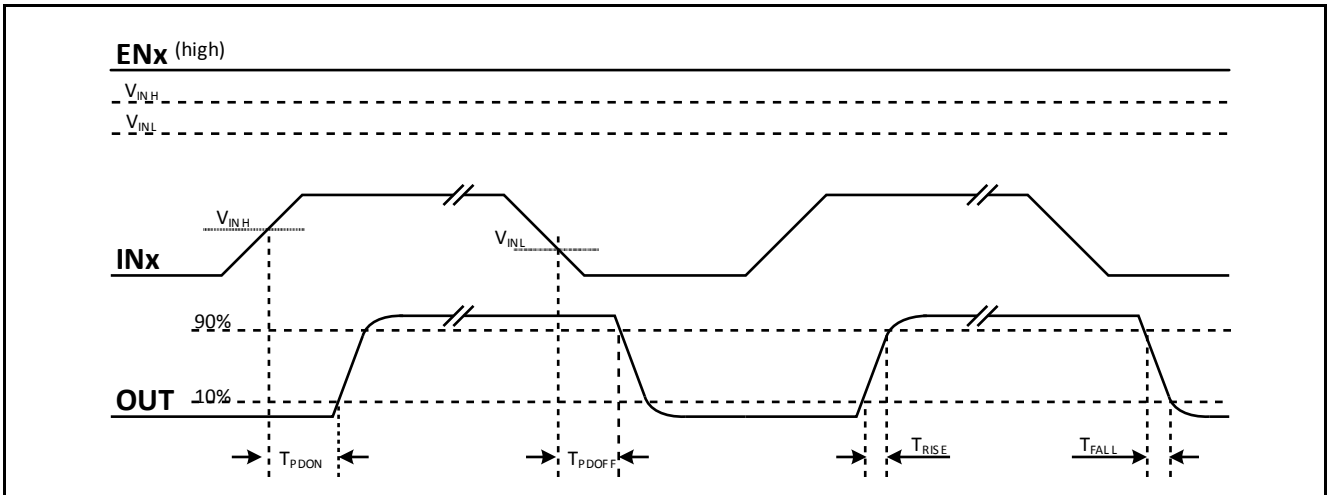


Figure 6-1 Propagation delay, rise and fall time, non-inverted

Figure 6-2 shows the definition of rise, fall and delay times for the inputs of the inverting version (with enable pins high or open).

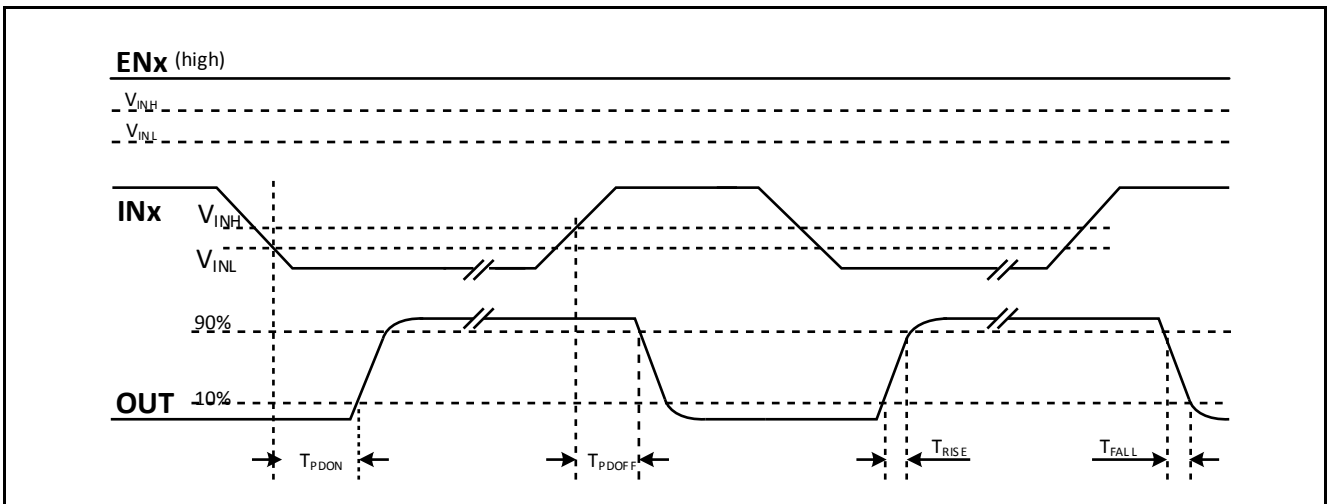


Figure 6-2 Propagation delay, rise and fall Time, inverted

Figure 6-3 illustrates the undervoltage lockout function.

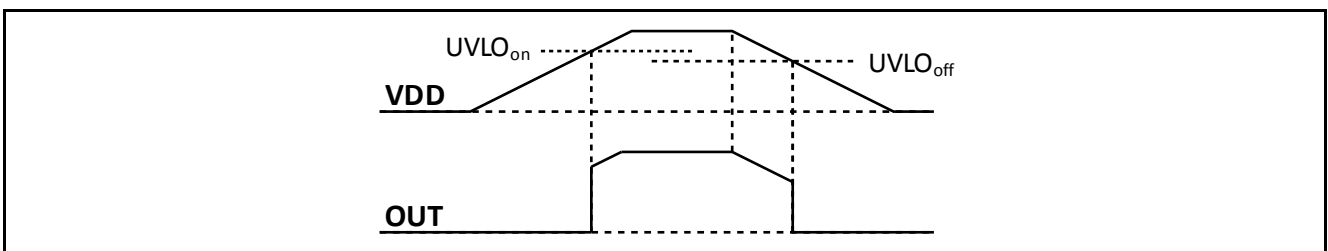


Figure 6-3 UVLO behaviour, input ENx and INx drives $OUTx$ normally high

Timing Diagrams

Figure 6-4 illustrates the minimum input pulse width that changes output state.

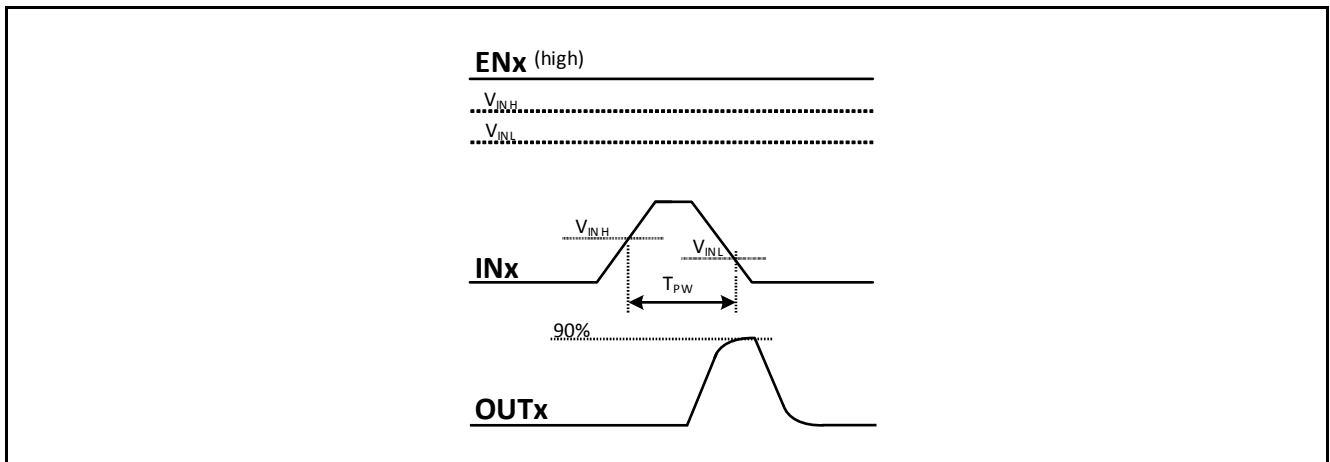


Figure 6-4 T_{PW} , minimum input pulse width that changes output state

Typical Characteristics

7 Typical Characteristics

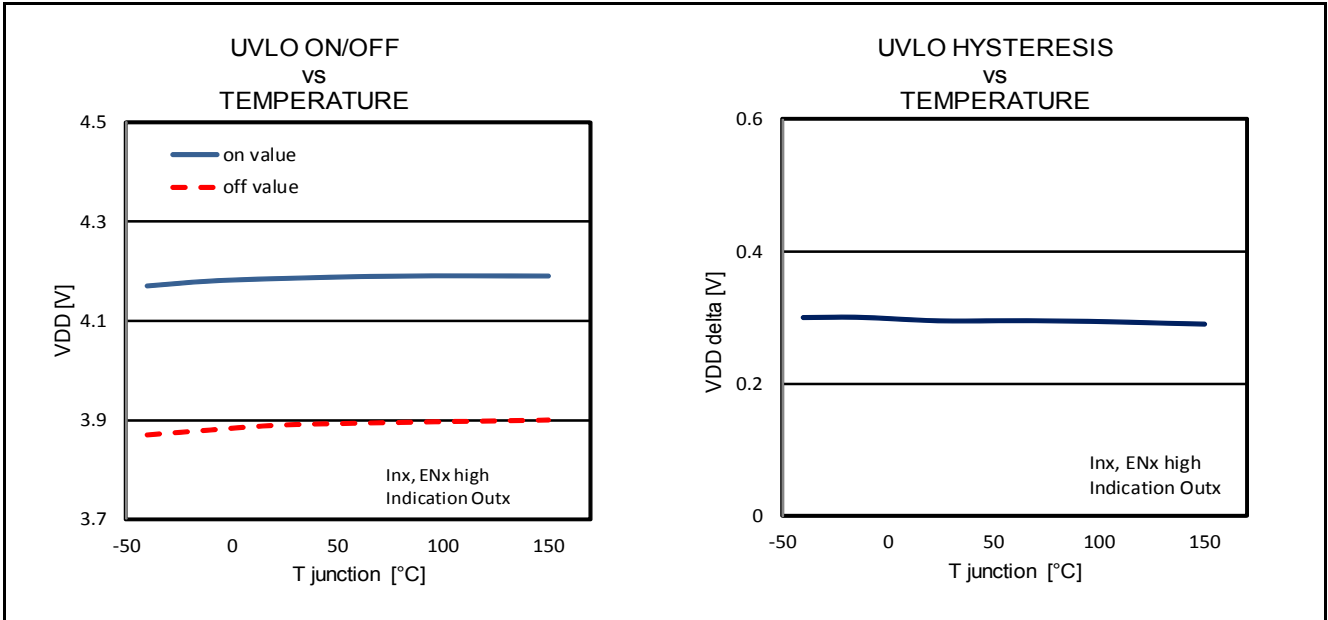


Figure 7-1 Undervoltage lockout 2ED7x (4.2V)

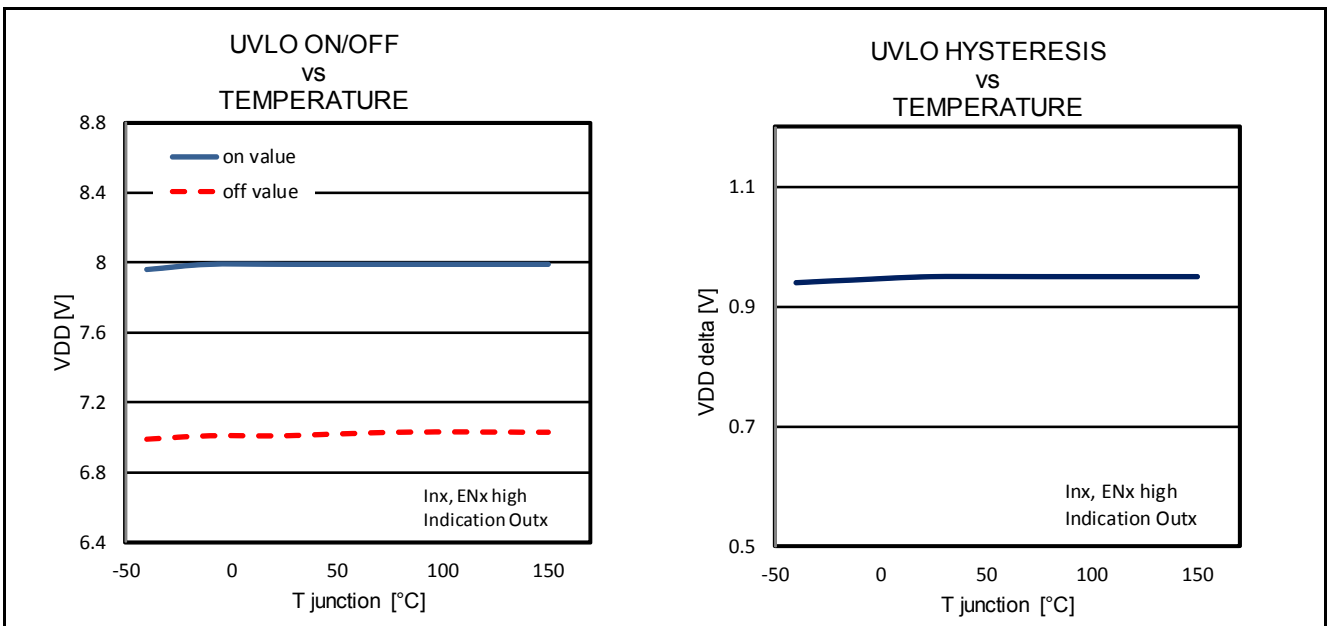


Figure 7-2 Undervoltage lockout 2ED8x (8V)

Typical Characteristics

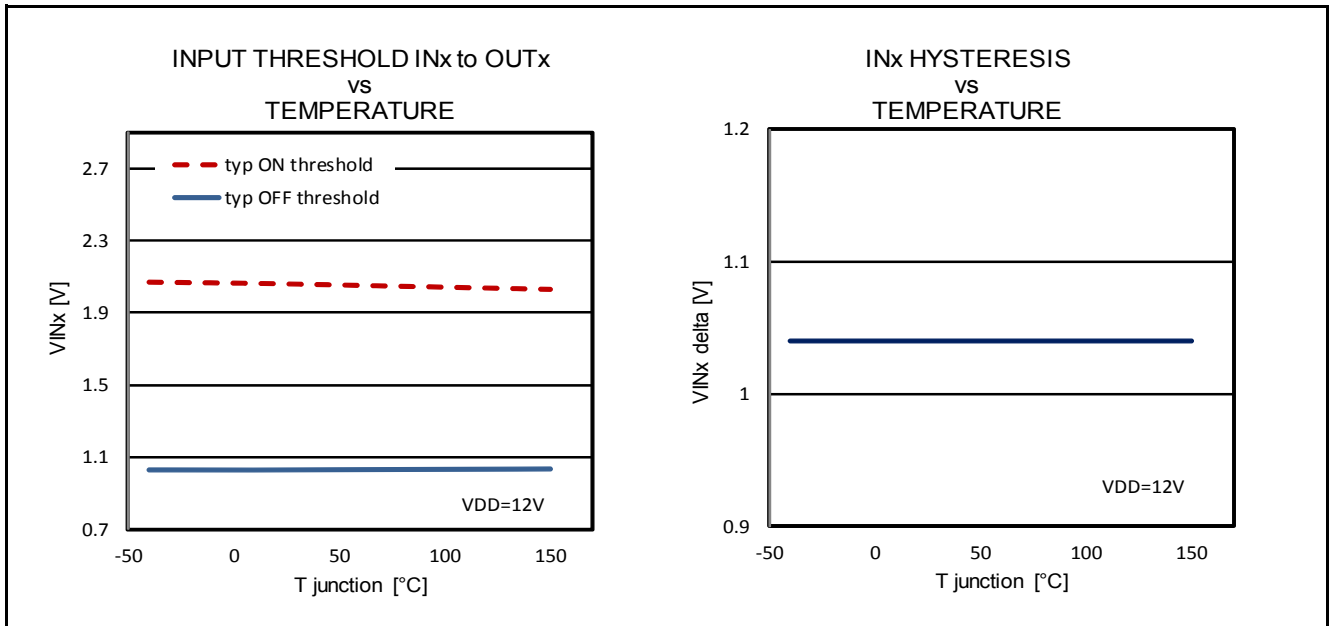


Figure 7-3 Input (INx) characteristic

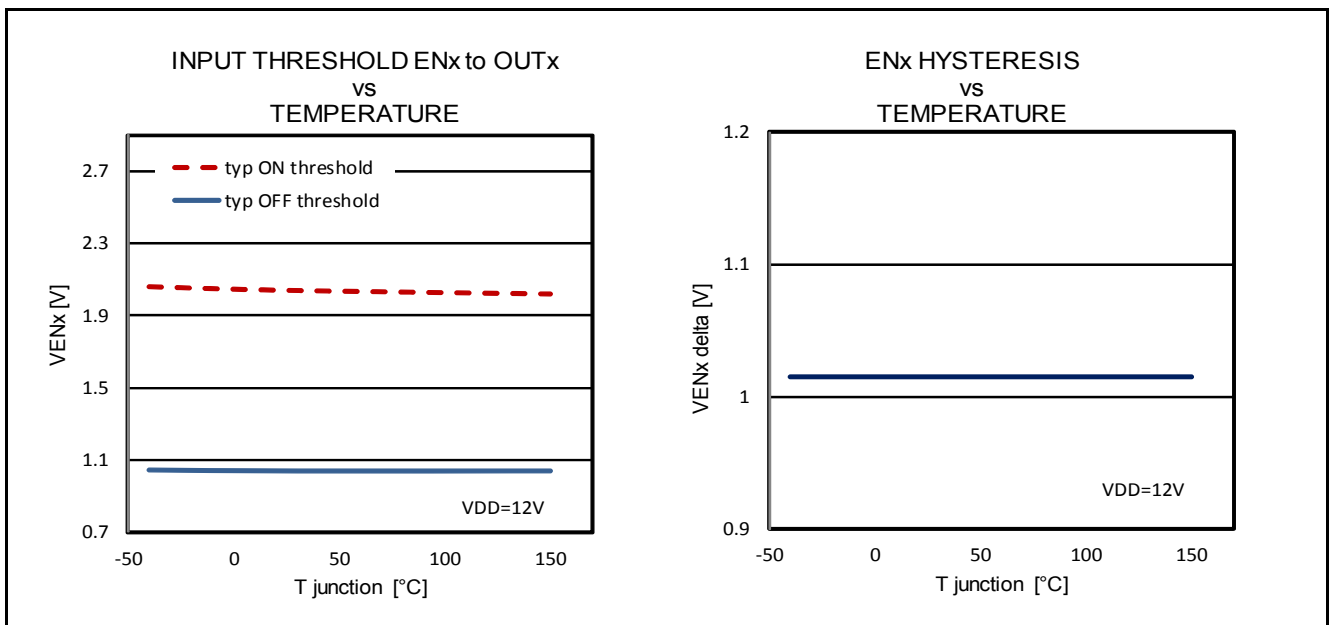


Figure 7-4 Input (ENx) characteristic

Typical Characteristics

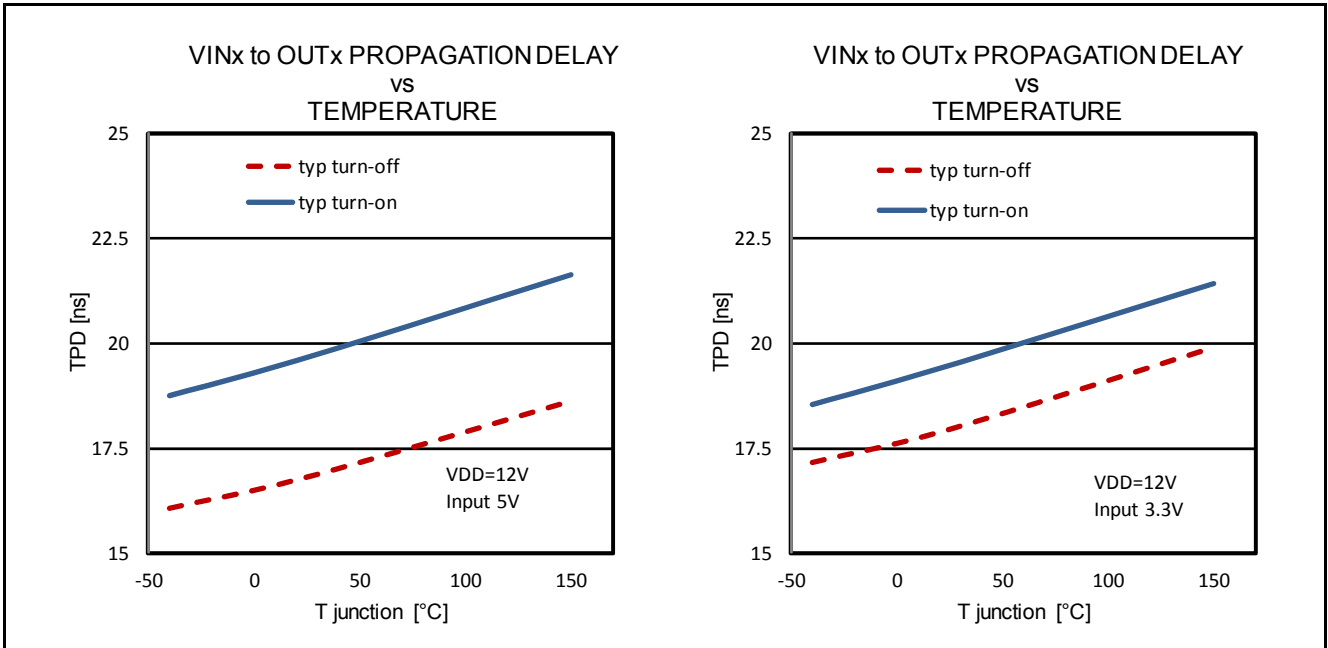


Figure 7-5 Propagation delay (INx) on different input logic levels (see Figure 6-1)

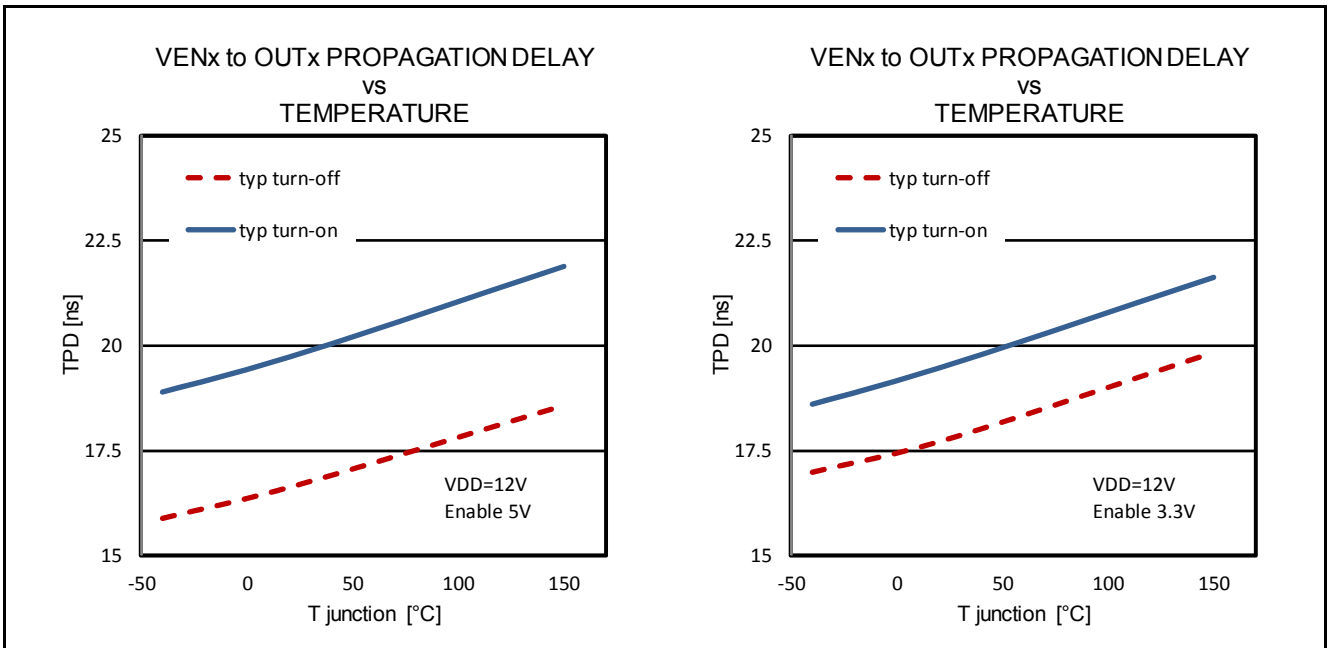


Figure 7-6 Propagation delay (ENx) on different input logic levels (see Figure 6-1)

Typical Characteristics

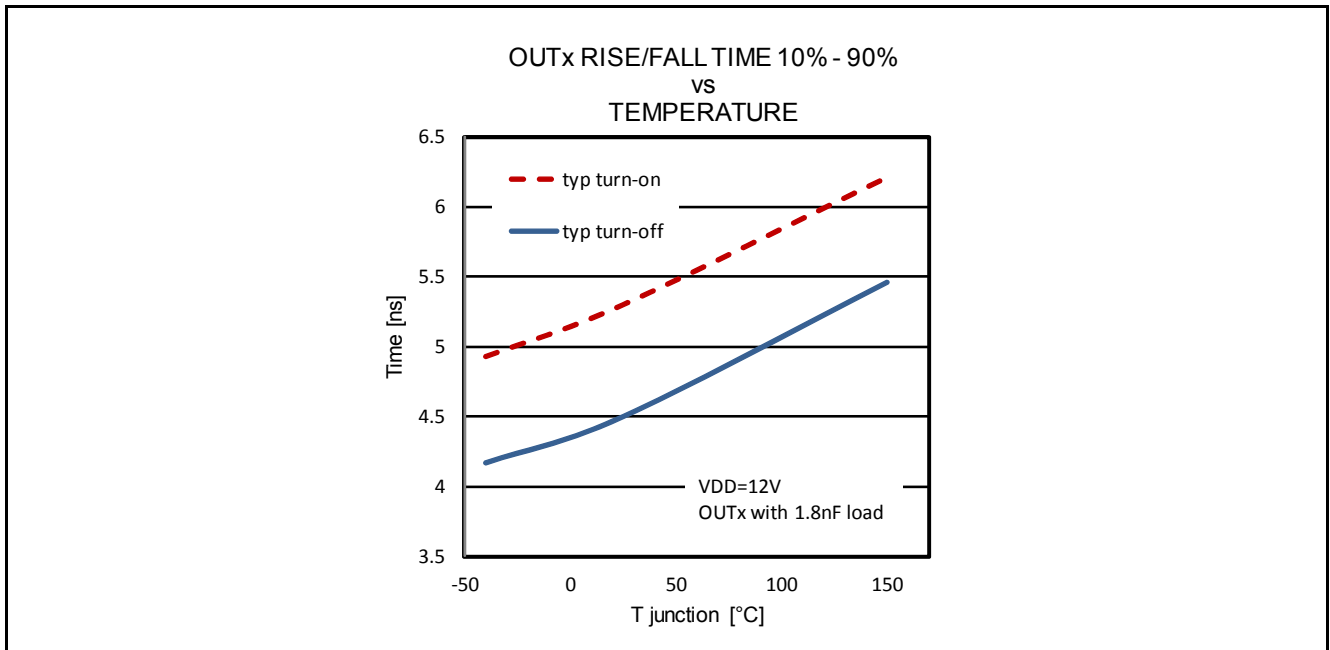


Figure 7-7 Rise / fall times with load on output (see [Figure 6-1](#))

Typical Characteristics

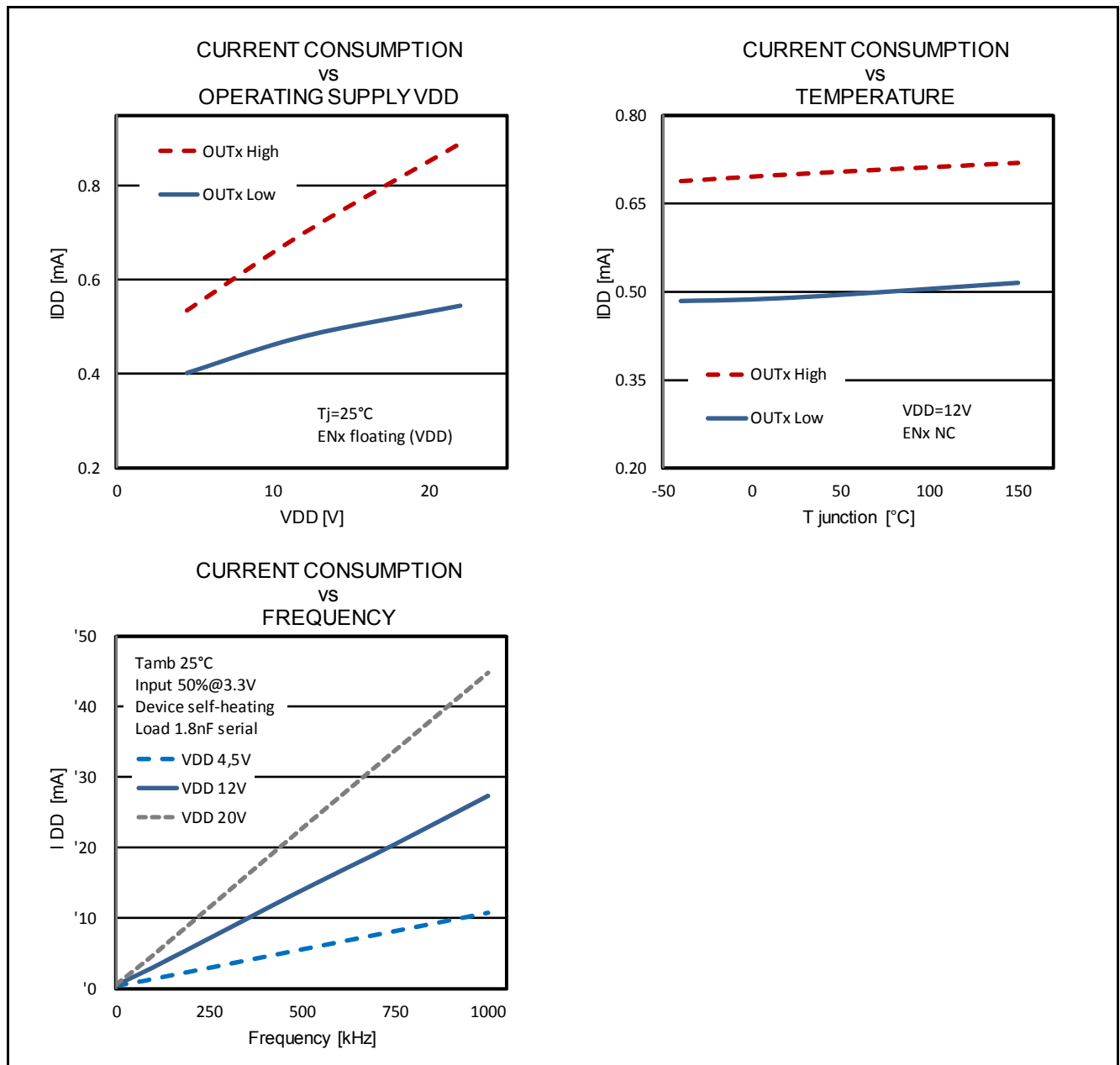


Figure 7-8 Power consumption related to temperature, supply voltage and frequency

Typical Characteristics

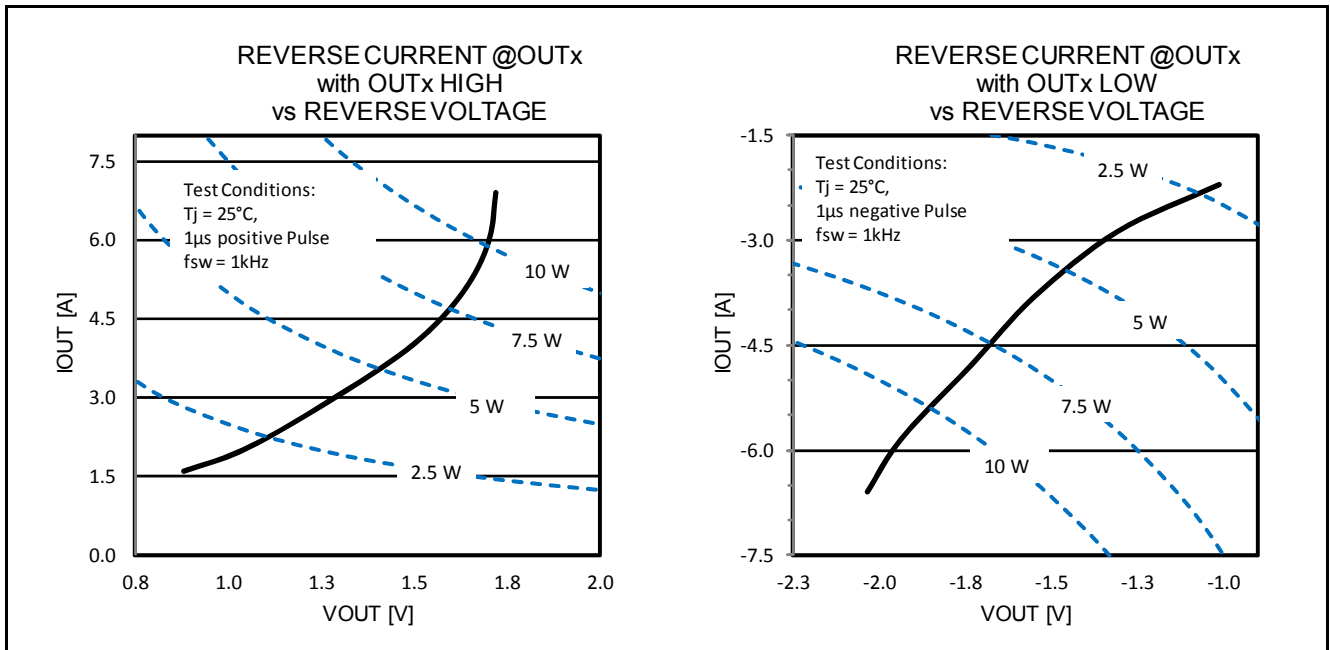


Figure 7-9 Output OUTx with reverse current and resulting power dissipation

Outline Dimensions

8 Outline Dimensions

Notes

- For further information on package types, recommendation for board assembly, please go to: <http://www.infineon.com/cms/en/product/technology/packages/>.

8.1 PG-DSO-8-60

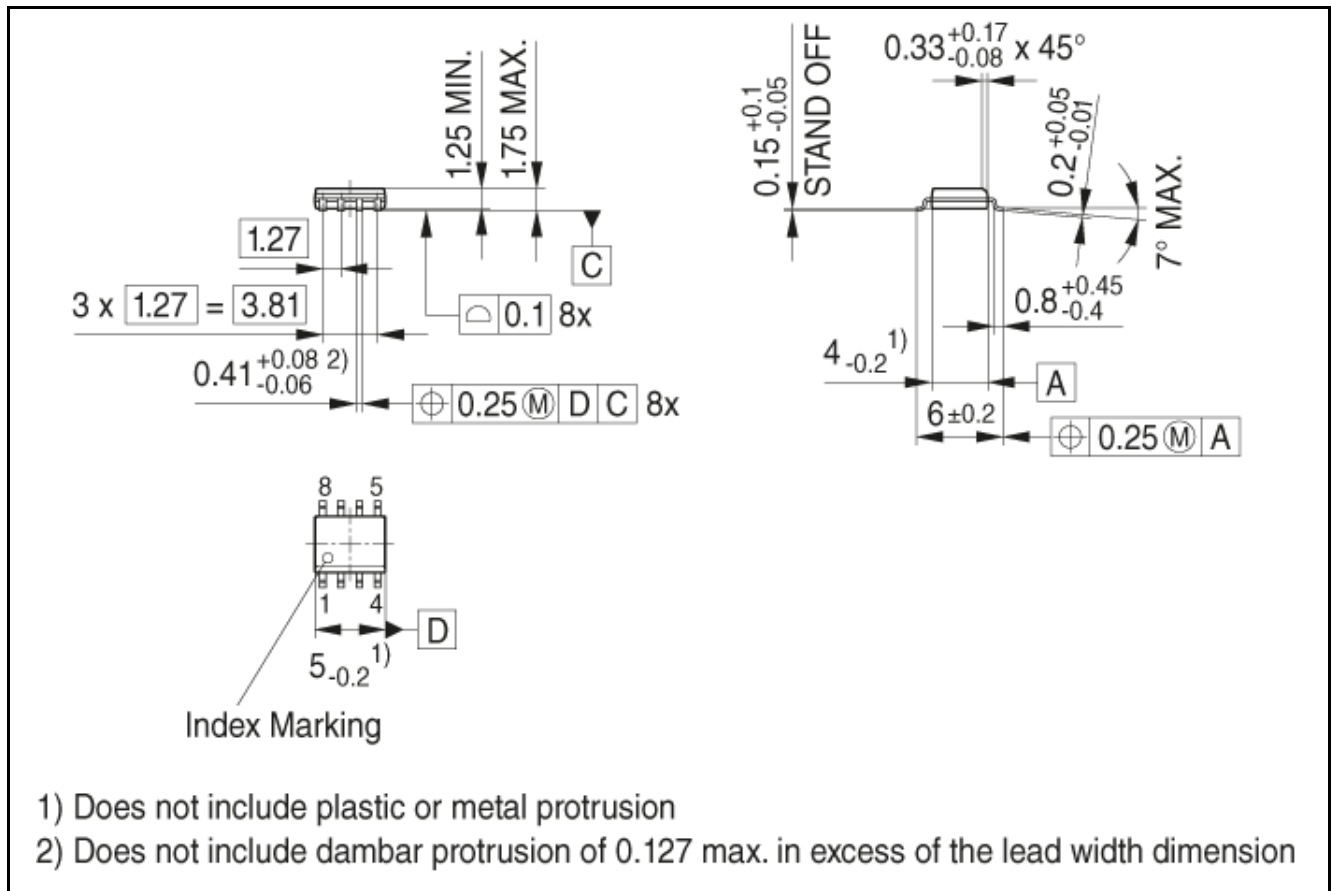


Figure 8-1 PG-DSO-8 outline

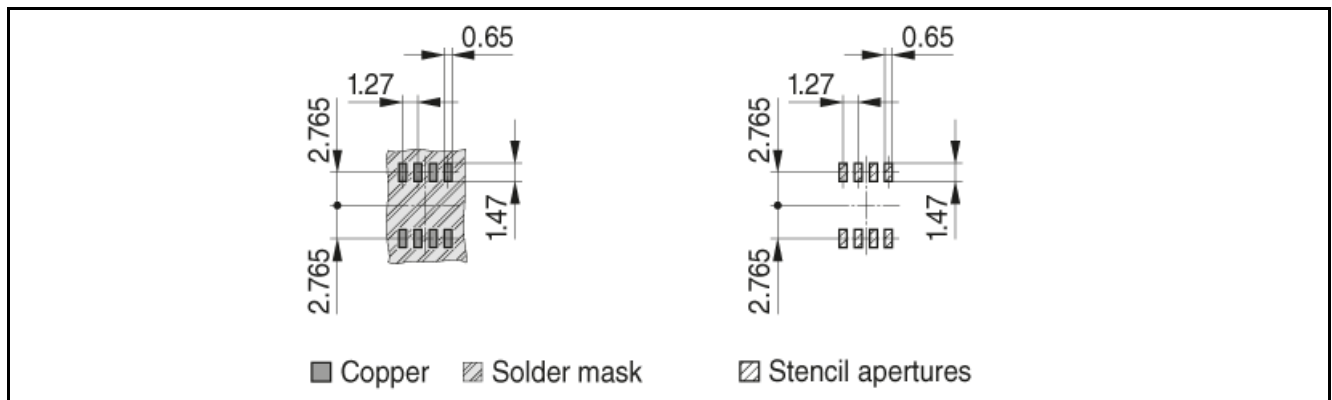


Figure 8-2 PG-DSO-8 footprint

Outline Dimensions

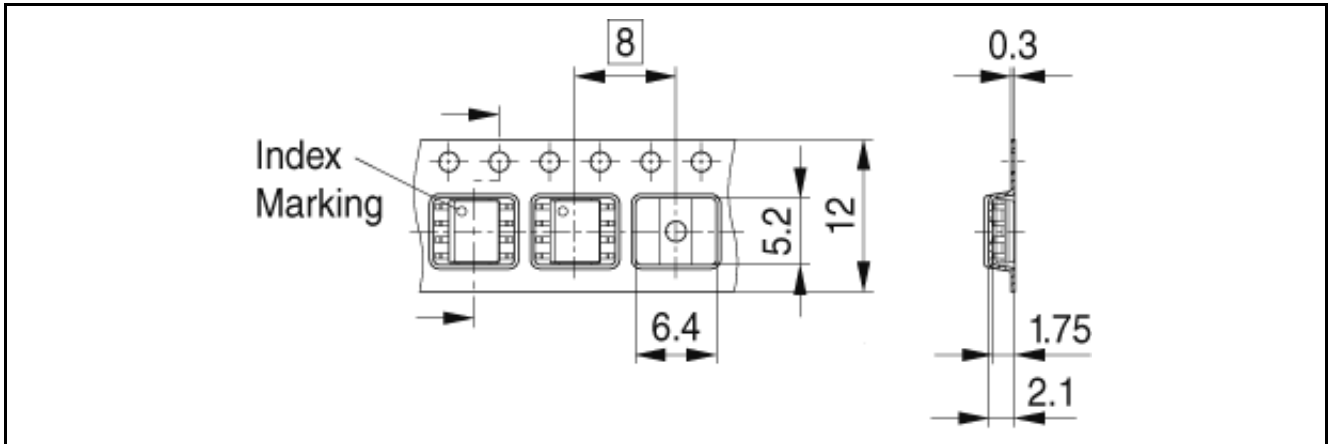


Figure 8-3 PG-DSO-8 packaging

8.2 PG-TSSOP-8-1

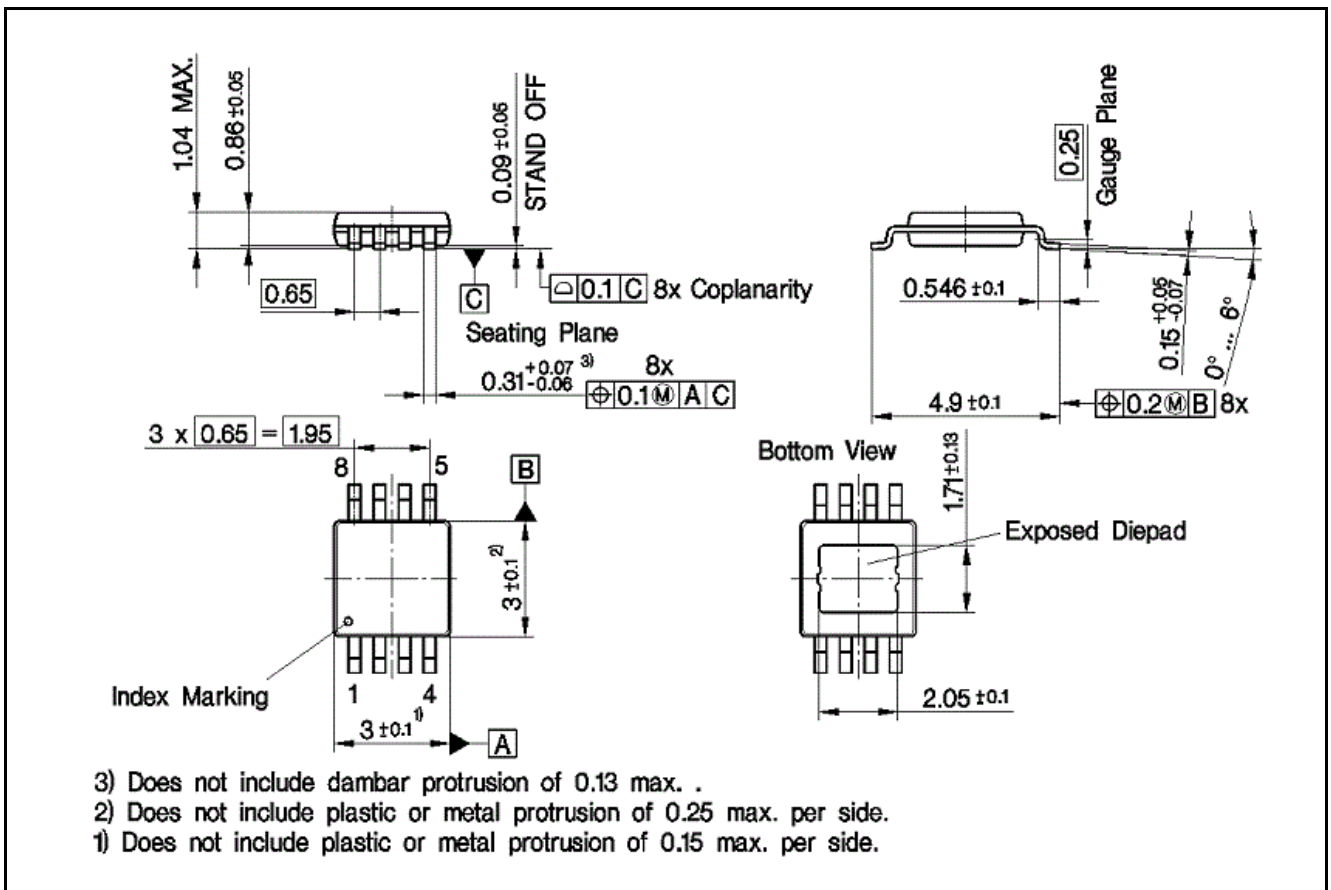


Figure 8-4 PG-TSSOP-8 outline

Outline Dimensions

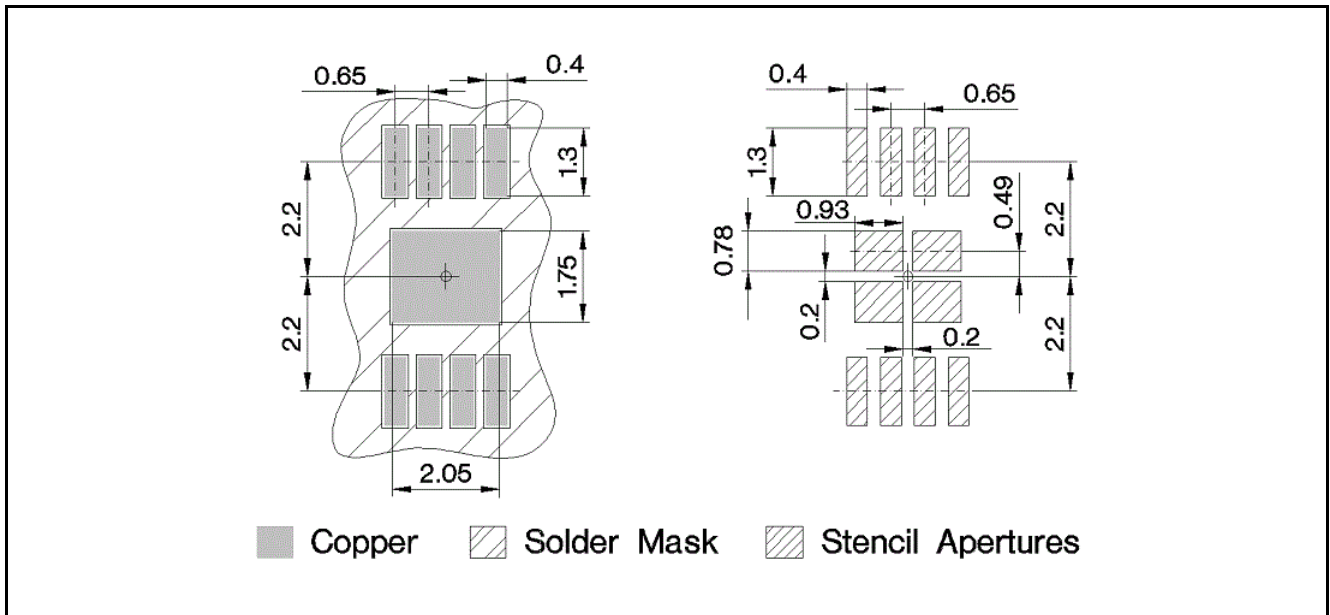


Figure 8-5 PG-TSSOP-8 footprint

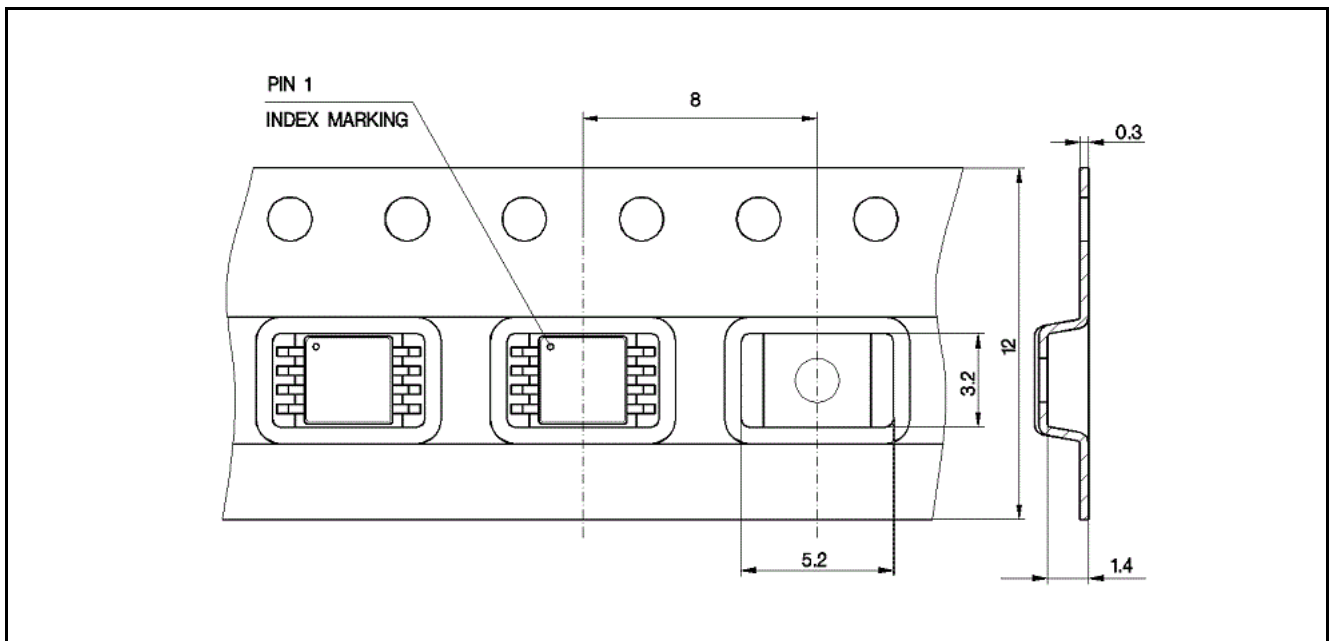


Figure 8-6 PG-TSSOP-8 packaging

Outline Dimensions

8.3 PG-WSO8-8-1

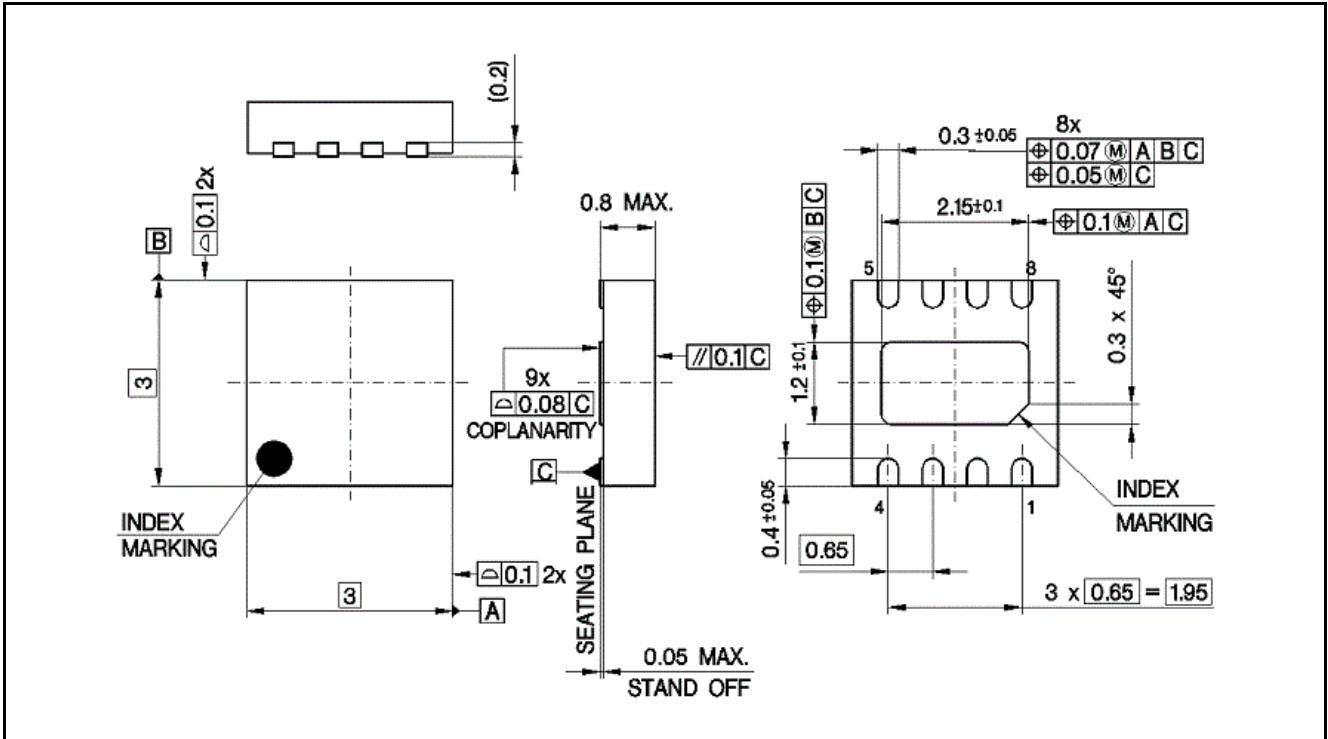


Figure 8-7 PG-WSO8-8 outline

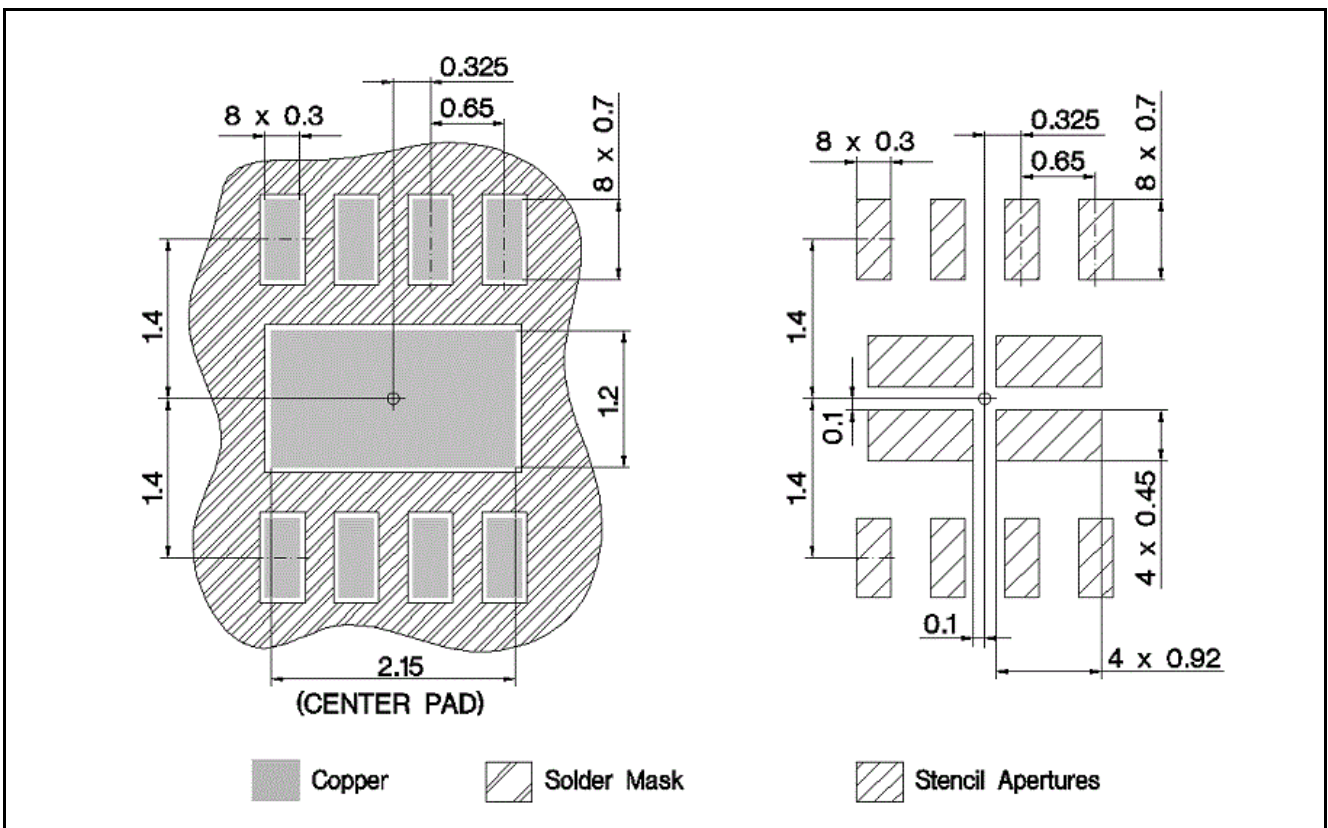


Figure 8-8 PG-WSO8-8 footprint

Outline Dimensions

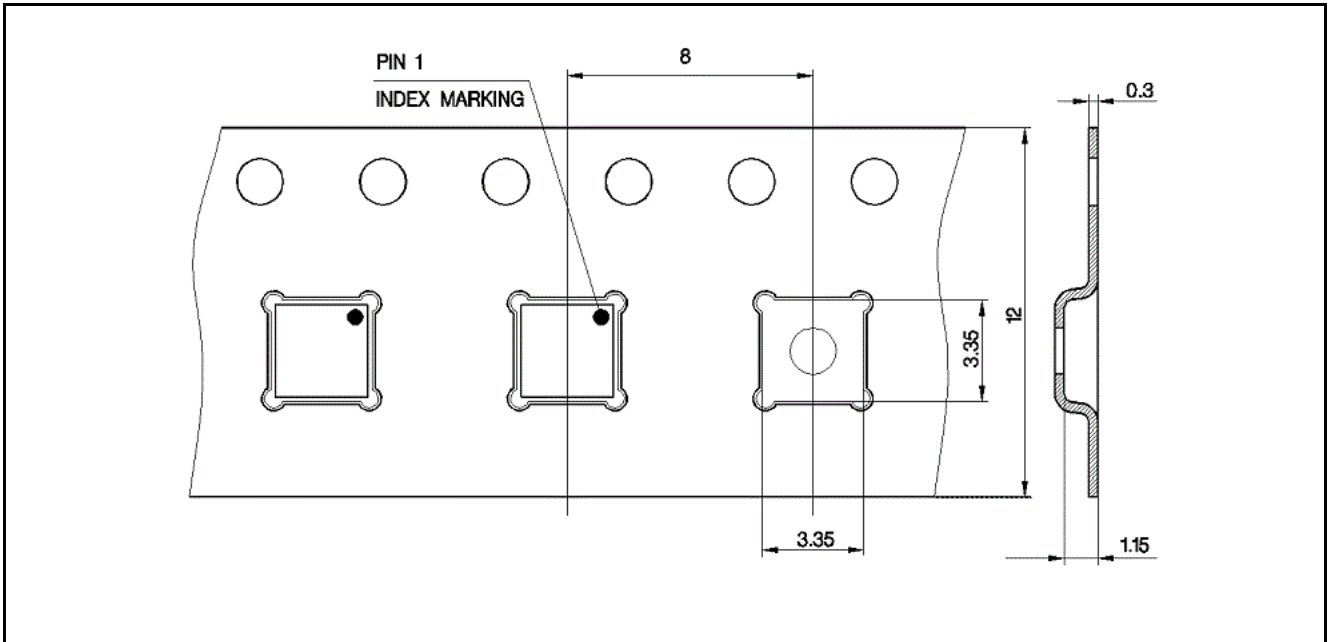


Figure 8-9 PG-WSON-8 packaging

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